

Sheet 1 of 2

Form PTO-1449 U.S. Department of Commerce (Modified) Patent and Trademark Office								Attorney Docket No.	Serial No.
<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>								S-100,500	
								Applicant(s)	
								Christopher J. Bulian et al.	
								Filing Date	Group
37 CFR 1.98(b)									

U.S. PATENTS DOCUMENTS													
EXAMINER INITIAL	PATENT NUMBER						ISSUE DATE	PATENTEE	CLASS	SUB CLASS	FILING DATE		
<i>PW</i>		5	9	1	1	9	6	5	06/15/1999	John A. Bailey et al.	423	606	01/23/1998
		4	5	8	6	1	4	3	04/29/1986	Masayoshi Kaneyasu et al.	364	509	01/28/1983
		5	8	1	1	6	6	2	09/22/1998	David Edward Williams et al.	73	31.06	06/20/1995
		4	2	3	3	3	3	9	11/11/1980	Marshall Leibowitz et al.	427	108	10/23/1978
		5	7	8	8	7	3	8	08/04/1998	Shahid Pirzada et al.	75	331	09/03/1996
		5	5	2	5	2	6	4	06/11/1996	John P. Cronin et al.	252	583	06/02/1995
↓		5	9	8	4	9	9	7	11/16/1999	Clint Bickmore et al.	75	343	03/23/1998

FOREIGN PATENT DOCUMENTS								
EXAMINER INITIAL	PATENT NUMBER			ISSUE DATE	COUNTRY	CLASS	SUB CLASS	Translation YES NO

OTHER DOCUMENTS (Including Author, Title, Date, Place of Publication)						
<i>PW</i>	J. P. Cronin, D. J. Tarico, J. C. L. Tonazzi, A. Agrawal, and S. R. Kennedy, "Microstructure and Properties of Sol-Gel Deposited WO <sub>3</sub> Coatings for Large Area Electrochromic Windows," Solar Energy Materials and Solar Cells, vol. 29, pp. 371-386, 1993					
1	M. A. Reiche, P. Hug, and A. Baiker, "Effect of Grafting Sequence on the Behavior of Titania-Supported V <sub>2</sub> O <sub>5</sub> -WO <sub>3</sub> Catalysts in the Selective Reduction of NO by NH <sub>3</sub> ," Journal of Catalysis, vol. 192, pp. 400-411, 2000					
↓	Xusheng Wang, Norio Miura, and Noboru Yamazoe, "Study of WO <sub>3</sub> -Based Sensing Materials for NH <sub>3</sub> , and NO Detection," Sensors and Actuators B, vol. 66, pp. 74-76, 2000					

EXAMINER: <i>Paul Wettre</i>	DATE CONSIDERED: <i>3/27/06</i>
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\*EXAMINER: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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<b>OTHER DOCUMENTS</b> (Including Author, Title, Date, Place of Publication)			
<i>RW</i>	I. Ruokamo, T. Karkkainen, J. Huusko, T. Ruokanen, M. Blomberg, H. Torvela, and V. Lantto, "H <sub>2</sub> S Response of WO <sub>3</sub> Thin-Film Sensors Manufactured By Silicon Processing Technology," Sensors and Actuators B, vol. 18-19, pp. 486-488, 1994		
	Ismael Jimenez, Jordi Arbiol, Albert Cornet, and Joan Ramon Morante, "Structural and Gas-Sensing Properties of WO <sub>3</sub> Nanocrystalline Powders Obtained by a Sol-Gel Method From Tungstic Acid," IEEE Sensors Journal, vol. 2, no. 4, pp. 329-335, August 2002		
	M. Regragui, M. Addou, A. Outzourkit, J. C. Bernede, Elb. El Idrissi, E. Benseddik, and A. Kachouane, "Preparation and Characterization of Pyrolytic Spray Deposited Electrochromic Tungsten Trioxide Films," Thin Solid Films, vol. 358, pp. 40-45, 2000		
	Morito Akiyama, Jun Tamaki, Norio Miura, and Noboru Yamazoe, "Tungsten Oxide-Based Semiconductor Sensor Highly Sensitive to NO and NO <sub>2</sub> ," Chemistry Letters, pp. 1611-1614, 1991		
	M. Gotic, M. Ivanda, S. Popovic, and S. Music, "Synthesis of Tungsten Trioxide Hydrates and Their Structural Properties," Materials Science and Engineering, vol. B77, pp. 193-201, 2000		
	Cs. Balazsi, M. Farkas-Jahnke, I. Kotsis, L. Petras, and J. Pfeifer, "The Observation of Cubic Tungsten Trioxide at High-Temperature Dehydration of Tungstic Acid Hydrate," Solid State Ionics, vol. 141-142, pp. 411-416		
<i>↓</i>	Cs. Balazsi, "Development of Tungsten Oxide Hydrate Phases During Precipitation-Washing-Ripening Process," Materials Structure, vol. 6, num. 6, pp. 135-139, 1999		
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